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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/633,055	07/31/2003	Shahriar Ahmed	42P10970C 3607		
75	590 09/25/2006	EXAMINER			
Michael A. Bernadicou			IM, JUNGHWA M		
BLAKELY, SC 12400 Willshire	OKOLOFF, TAYLOR & 2 Boulevard	ART UNIT	PAPER NUMBER		
Seventh Floor,		2811			
			DATE MAILED: 09/25/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

* "		Applicatio	n No.	Applicant(s)			
Office Action Summary		10/633,05	5	AHMED ET AL.			
		Examiner		Art Unit			
		Junghwa N	1. lm	2811			
 Period for	The MAILING DATE of this communicat			orrespondence ad	idress		
A SHO THE M - Extensi after SI - If the p - If NO p - Failure Any rep	RTENED STATUTORY PERIOD FOR AILING DATE OF THIS COMMUNICA ions of time may be available under the provisions of 31 IX (6) MONTHS from the mailing date of this communic eriod for reply specified above is less than thirty (30) date of or reply is specified above, the maximum statuto to reply within the set or extended period for reply will, oly received by the Office later than three months after the patent term adjustment. See 37 CFR 1.704(b).	TION. 7 CFR 1.136(a). In no eve ation. 1ys, a reply within the statury period will apply and will by statute, cause the appli	nt, however, may a reply be tim tory minimum of thirty (30) days expire SIX (6) MONTHS from cation to become ABANDONEI	nely filed s will be considered timel the mailing date of this c D (35 U.S.C. § 133).	ly. communication.		
Status							
1)⊠ F	Responsive to communication(s) filed o	n <u>30 June 2006</u> .					
2a)⊠ T	This action is <b>FINAL</b> . 2b)	This action is no	on-final.				
, —	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Dispositio	n of Claims						
4: 5)□ ( 6)□ ( 7)⊠ (	Claim(s) 13,17-22 and 27-31 is/are pen  a) Of the above claim(s) is/are v  Claim(s) is/are allowed.  Claim(s) is/are rejected.  Claim(s) 13,17-22 and 27-31 is/are objection  Claim(s) are subject to restriction	vithdrawn from cor ected to.	sideration.				
Applicatio	n Papers						
10)□ T A F	he specification is objected to by the E he drawing(s) filed on is/are: a) Applicant may not request that any objection Replacement drawing sheet(s) including the he oath or declaration is objected to by	accepted or b)[ n to the drawing(s) be correction is require	e held in abeyance. See ed if the drawing(s) is obj	e 37 CFR 1.85(a). lected to. See 37 C			
Priority un	nder 35 U.S.C. § 119						
<ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of: <ol> <li>Certified copies of the priority documents have been received.</li> <li>Certified copies of the priority documents have been received in Application No.</li> <li>Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> </ol> </li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>							
Attachment(	s)						
2) Notice 3) Informa	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO- ation Disclosure Statement(s) (PTO-1449 or PTO- No(s)/Mail Date		4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:		O-152)		

Application/Control Number: 10/633,055

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## **DETAILED ACTION**

## Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 13, 17-22 and 27-31 are rejected under 35 U.S.C. 103(a) as being unpatentable over Akbar et al. (U.S. Pat. No. 4957875), hereinafter Akbar in view of Harame et al. (U.S. Pat. No. 5024957), hereinafter Harame.

Regarding claim 13, Fig. 8 of Akbar shows a bipolar junction transistor comprising: in a substrate 32, a first isolation structure 36 spaced apart from a second isolation structure 38;

a base 14, 22 formed in the substrate;

an emitter stack 16 disposed above the substrate and between the first isolation structure and the second isolation structure;

a recess (a portion between the regions 17, 18) disposed immediately adjacent to the emitter stack and disposed between the emitter stack and the first isolation structure, wherein the recess exposes a collector tap 26, wherein the emitter stack and the recess share a boundary; and

an emitter cut (an emitter/base junction) provide at the bottom of said emitter stack and on top of an intrinsic base structure (a portion of the base in contact with the emitter) formed in the substrate.

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Fig. 8 of Akbar shows most aspect of the instant invention except an intrinsic base formed in the epitaxial base. Fig. 9 of Harame shows a semiconductor device wherein an intrinsic base 32 formed in the epitaxial base 32A (col. 4, lines 10-16) is formed in the substrate. It would have been obvious to one of ordinary skill in the art at the time of the invention to incorporate the teachings of Harame into the device of Akbar in order to have an intrinsic base in the epitaxial base formed in the substrate to alleviate the leakage current.

Note that "epitaxial" is a process designation, and would not carry patentable weight in this claim drawn to a product. See *In re Thorp*, 227 USPO 964 (Fed. Cir. 1985).

Regarding claim 17, Fig. 8 of Akbar shows a buried layer 34 in the substrate between the first isolation structure and the second isolation structure.

Regarding claim 18, Fig. 8 of Akbar shows a bipolar junction transistor further including: a collector structure 12 disposed in the substrate below the emitter stack; and an intrinsic base structure 14 disposed between the emitter stack 16 and the collector structure 12.

Regarding claim 19, Fig. 8 of Akbar shows a bipolar junction transistor further including: a collector structure 12 disposed in the substrate below the emitter stack; and a dielectric layer 18, 20 disposed above the substrate and below the emitter stack and above the collector structure; and

an intrinsic base structure 14 disposed between the emitter stack and the collector structure.

Fig. 8 of Akbar shows most aspect of the instant invention except "the dielectric layer is patterned for said emitter cut to be formed therein." Fig. 9 of Harame shows a semiconductor

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device wherein the dielectric layer 34, 36 is patterned for the emitter cut (a bottom portion of the emitter 40) to be formed therein. It would have been obvious to one of ordinary skill in the art at the time of the invention to incorporate the teachings of Harame into the device of Akbar in order to have to a semiconductor device wherein the dielectric layer patterned for the emitter cut to reduce parasite capacitance between the emitter and the extrinsic base.

Regarding claim 20, Fig. 8 of Akbar shows a collector tap 26 is N type.

Regarding claim 21, Akbar discloses that the substrate includes a BiCMOS structure (col. 1, lines 11-14).

Regarding claim 22, Fig. 8 of Akbar shows the BJT is selected from a monojunction BJT device and a heterojunction BJT device.

Regarding claim 27, Fig. 8 of Akbar shows the collector tap 127 is self-aligned with the emitter stack.

Also, note that "self-aligned" is a process designation and would thus not carry patentable weight in this claim drawn to a product. See *In re Thorp*, 227 USPQ 964 (Fed. Cir. 1985).

Regarding claim 28, Fig. 8 of Akbar shows the bipolar junction transistor is an NPN transistor, and the collector tap is N type.

Regarding claim 29, Akbar discloses the bipolar junction transistor is an PNP transistor, and the collector tap is P type (col. 3, lines 24-25).

Regarding claim 30, Fig. 8 of Akbar shows the collector tap has no doping that is different from the substrate.

Regarding claim 31, Fig. 8 of Akbar shows the recess is a contact corridor.

Applicant's arguments filed June 30,2006 have been fully considered but they are not persuasive.

Applicants argue that "In Akbar, the whole emitter section contacts the base section 14 and 22. In other words, the entire width of the emitter section is formed on the base area. As such, Akbar did not disclose an emitter cut as recited in the claim. Contrary to Akbar, Applicant's disclosure includes a construction of an emitter cut from an emitter stack such that not all bottom section of the emitter stack is in contact with the base as can be seen from Figures 2-5 of the Application Drawings. Applicant's claimed invention as recited in claim 13, for example, claims an emitter cut provided at the bottom of said emitter stack and immediately on top of an intrinsic base structure formed in epitaxial base laver of the substrate." Examiner disagrees. Note that the instant invention does not recite such a limitation of the emitter as argued above. The instant invention recites that "an emitter stack disposed above the substrate and between the first isolation structure and the second isolation structure" and Akbar shows this aspect. Harame is further referred to show an intrinsic base formed in the epitaxial base in the substrate. Therefore, the combined teachings of Akbar and Harame would result in a structure of an emitter cut provided at the bottom of said emitter stack and immediately on top of an intrinsic base structure formed in epitaxial base layer of the substrate.

## Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Junghwa M. Im whose telephone number is (571) 272-1655. The examiner can normally be reached on MON.-FRI. 8:30AM-5:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's acting supervisor, Eddie C. Lee can be reached on (571) 272-1732. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

jmi

EDDIE LEE

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